

# Local False Discovery Rates

- ① Multiple Testing
- ② False Discovery Rate
- ③ Empirical Bayes for Multiple Testing
- ④ Estimating Ifdr

# ① Multiple Testing

## ② False Discovery Rate

## ③ Empirical Bayes for Multiple Testing

## ④ Estimating Ifdr

# Multiple testing

- **Motivation:** High-throughput studies (e.g. genomics, fMRI) routinely test *thousands* of genes or features at once.
- **Per-test vs. global error:** If each hypothesis is tested at level  $\alpha$  and the  $m$  tests are (approximately) independent,

$$\Pr(\text{at least one false positive}) = 1 - (1 - \alpha)^m \approx m\alpha \quad (\alpha \ll 1).$$

- **Need for global error measures:**
  - *Family-Wise Error Rate (FWER)*: controls the probability of *any* false positive but is often overly conservative in large-scale settings.
  - We seek an error metric that:
    - ① maintains meaningful error control;
    - ② does *not* scale with  $m$ ;
    - ③ preserves higher power in large-scale settings.

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# False discovery rates (FDR)

- **Problem setting**

- We simultaneously test  $m$  null hypotheses

$$H_{0,i} : \theta_i = 0 \quad \text{vs.} \quad H_{1,i} : \theta_i \neq 0, \quad i = 1, \dots, m,$$

producing test statistics (or  $p$ -values)  $p_1, \dots, p_m$ .

- Let

$$V = \#\{\text{false positives}\}, \quad R = \#\{\text{total rejections}\}.$$

- **Definition**

$$\text{FDR} = \mathbb{E}\left[\frac{V}{R}\right]$$

( set  $V/R = 0$  when  $R = 0$ .)

- **Interpretation:** FDR is the expected fraction of reported discoveries that are actually null.

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# Empirical Bayes: Two Group Model

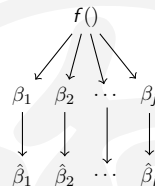
- **Two group model:**

$$f(z) = \pi_0 f_0(z) + \pi_1 f_1(z)$$

- $f_0(z)$ : density under the null.
- $f_1(z)$  density under the alternative.
- $\pi_0$ : prior probability that an effect is null.
- $\pi_1$ : prior probability that an effect is non-null. ( $\pi_1 = 1 - \pi_0$ ).

- **Empirical Bayes idea:** Estimate the prior parameters ( $\pi_0, f_0, f_1$ ) directly from the observed data, then use those point estimates to compute posterior quantities such as the local false discovery rates.

Effects Distribution



Deconvolution view



# Local False Discovery Rate (lfdr)

- **Local false discover rates**

$$\text{lfdr}(z) = P(\text{null} \mid Z = z) = \frac{P(Z = z \mid \text{null}) P(\text{null})}{P(Z = z)} = \frac{\pi_0 f_0(z)}{f(z)}.$$

- **Empirical Bayes plug-in estimate**

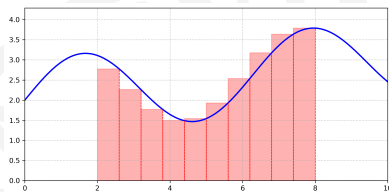
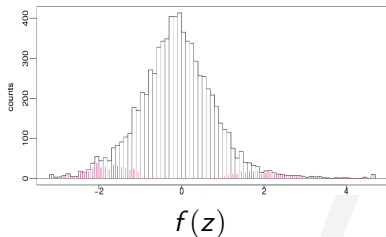
$$\widehat{\text{lfdr}}(z) = \frac{\widehat{\pi}_0 \widehat{f}_0(z)}{\widehat{f}(z)},$$

- **Controlling FDR with  $\widehat{\text{lfdr}}$**

1. Sort  $\widehat{\text{lfdr}}_{(1)} \leq \dots \leq \widehat{\text{lfdr}}_{(m)}$ ;
2. Find  $k^* = \max \left\{ k : \frac{1}{k} \sum_{i=1}^k \widehat{\text{lfdr}}_{(i)} \leq \alpha \right\}$ ;
3. Reject  $k^*$  nulls.

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# Estimating $f(z)$ : overview



Riemann integral

$$f(z) \xrightarrow{\text{binning}} \lambda_k = N \Delta f(z_{(k)}) \xrightarrow{\text{counts}} y_k \sim \text{Poisson}(\lambda_k) \xrightarrow{\text{Poisson GLM}} \hat{f}(z)$$

## Step 1: Thin-binned histogram of z-scores

- **Input data**:  $z_1, \dots, z_N$  —one z-score per test, assumed i.i.d. from the unknown marginal density  $f(z)$ .
- **Choose a small bin width**  $\Delta$  (Efron uses  $\Delta \approx 0.2$ ). Create contiguous, non-overlapping bins

$$B_k = [a_k, a_k + \Delta), \quad k = 1, \dots, K.$$

- **Bin centres**:

$$z_{(k)} = a_k + \frac{\Delta}{2}, \quad k = 1, \dots, K.$$

- **Count within each bin**:

$$y_k = \#\{i : z_i \in B_k\}, \quad \sum_{k=1}^K y_k = N.$$

- **Dataset**:  $\{(y_k, z_{(k)})\}$

## Step 2: Binomial $\rightarrow$ Poisson Approximation

- **Binomial sampling model** Each  $z_i$  falls into exactly one thin bin  $B_k$ , so the count

$$y_k \sim \text{Bin}(N, \pi_k), \quad \pi_k = \Pr\{Z \in B_k\}.$$

- **Link to the unknown density**

$$\pi_k = \int_{B_k} f(z) dz \approx f(z_{(k)}) \Delta \quad \text{for thin bins } (\Delta \text{ small}).$$

- **Poisson Approximation** When  $N$  is large and  $\pi_k$  is small (typical in high-throughput settings),

$$\text{Bin}(N, \pi_k) \implies \text{Pois}(\lambda_k), \quad \lambda_k = N \pi_k \approx N \Delta f(z_{(k)}).$$

- **Implication for estimation** The  $(z_{(k)}, y_k)$  pairs can now be viewed as Poisson responses with mean  $\lambda_k$ —exactly the structure needed to fit a Poisson generalized linear model in Step 3 and obtain the smooth estimator  $\hat{f}(z)$ .

## Step 3: Poisson GLM to obtain $\hat{f}(z)$

- **Model for binned counts** From Step 2 we treat the histogram counts as

$$y_k \sim \text{Pois}(\lambda_k), \quad \lambda_k = N \Delta f(z_{(k)}).$$

- **Log-linear specification**

$$\log \lambda_k = \log(N\Delta) + \beta_1 g_1(z_{(k)}) + \cdots + \beta_p g_p(z_{(k)}),$$

where  $\log(N\Delta)$  is an *offset* and  $g_j(\cdot)$  are user-chosen smooth functions.

- **Recovering the density**

$$\hat{f}(z) = \exp\left(\sum_{j=1}^p \hat{\beta}_j g_j(z)\right), \quad \hat{\beta}_0 = -\log\left[\int \exp(\sum_j \hat{\beta}_j g_j(u)) du\right]$$

# Estimating the Empirical Null $f_0()$

- **Theoretical null (ideal case)**

$$f_0(z) = \phi(z) = \frac{1}{\sqrt{2\pi}} e^{-z^2/2},$$

- **Real-data departures** Correlation, hidden covariates or scale shifts can produce  $Z \sim \mathcal{N}(\mu_0, \sigma_0^2)$ ,
- **Empirical null: two estimation strategies**
  - ① *Central matching* —fit a quadratic to  $\log \hat{f}(z)$  over a central window (e.g.  $|z| \leq 2$ ), then solve for  $\hat{\mu}_0, \hat{\sigma}_0$ .
  - ② *MLE zero-assumption* —label all observations in  $|z| \leq z_0$  (typ.  $z_0 = 1$ ) as null and maximise  $\prod \phi_{\mu_0, \sigma_0}(z_i)$  to obtain  $\hat{\mu}_0, \hat{\sigma}_0$ .

## Step 4: Estimating $\pi_0$ (Central Matching)

- **Mostly-null window**: pick a central band (e.g.  $|z| \leq 2$ ) where  $f(z) \approx \pi_0 f_0(z)$ .
- **Quadratic fit**:

$$\log \hat{f}(z) \approx a_0 + a_1 z + a_2 z^2, \quad |z| \leq 2.$$

- **Coefficient comparison**: match this expansion to  $\log[\pi_0 f_0(z)] = \log \pi_0 + \log f_0(z)$  where  $\log f_0(z)$  itself is quadratic.

$$\log f_0(z) = -\frac{1}{2\sigma_0^2} z^2 + \frac{\mu_0}{\sigma_0^2} z - \left( \frac{\mu_0^2}{2\sigma_0^2} + \frac{1}{2} \log 2\pi\sigma_0^2 \right).$$

- $a_2 \rightarrow \sigma_0$
- $a_1 \rightarrow \mu_0$
- $a_0 \rightarrow \pi_0$  via  $a_0 = \log[\pi_0 f_0(0)]$

Thus all empirical-null parameters are identified by the fitted coefficients.